

MUNICH, GERMANY DECEMBER 6 - 7, 2022

An Accelerated System Level CPU Verification through Simulation-Emulation Co-Existence

Ruchi Misra, Samridh Deva, P Sai Krishna, Alok Kumar, Garima Srivastava YoungSik Kim, Seonil Brian Choi

SAMSUNG



SYSTEMS INITIATIVE

Outline

- Need for adoption of Emulation in early Design Verification
- Pre-Silicon Verification flow
- Emulator Compilation flow
- Methodology
- Case Studies
- Enhancements done
- Results
- Conclusion
- Future Scope and Care Abouts
- Acknowledgement





Need for adoption of Emulation in early Design Verification



Source: Wilson Research Group and Mentor, A Siemens Business, 2020 Functional Verification Study





Introduction



- Shrinking turn around times
- Need for faster simulations and quicker results
- Delay in time to market





Motivation







Pre-Silicon Verification Flow





Emulation Platform







Emulation Compilation Flow





Compilation Parameters

Environment



Motivation for Power Aware Verification at SoC

- Power-aware Verification of SoCs has been around for over a decade ever since IEEE released the UPF standard.
- Today, we not only have multi-core SoC designs but also multi-cluster SoCs with dual architecture processors implemented on the same die.
- Needless to say, this increase in complexity due to SoC architecture evolution has seeped into the requirements of power-aware verification and is fast becoming the long-pole of the verification lifecycle.
- We divided the power-aware verification requirements into a number of test categories and successfully accelerated the power-aware verification lifecycle with the use of emulators by incorporating UPF design libraries and power domain control into the design images used for emulation-based verification.
- This has resulted in up to 40x savings in time and resources.





Basic Methodology







Case-Study 1: Complex Coherency Scenario





Case-Study 2: Dynamic Voltage and Frequency Scaling

Ways to reduce power consumption of chips on the fly

Different Design Blocks at SoC work on different frequency

Verification team has to traverse through all the frequencies for testing

Testing/Scaling of frequencies for memory interface, cores, coherent interconnects etc take huge simulation time !









Case-Study 3: Low Power Scenarios

- ✓ Various low power scenarios at Emulation level
- ✓ Core/Cluster Clock Gating schemes, Memory Retention schemes as well as complete power down and sleep scenarios for various blocks of SoC.
- ✓ Figure shows different processor states possible and the waveform shows a typical Power Down scenario for Cores and Cluster which can be verified using emulator in an efficient manner.
- ✓ These low power scenarios are also run in Power-Aware setup with UPF incorporated.









Methodology : Low Power Set-up

- Both UPF files and RTL files are fed to the EDA tool which understands the power intent of the design through UPF files and functional intent from design files.
- □ After the process of analysis, elaboration and splitting, and then synthesis, EDIF files are produced which is a vendor-neutral file format used to store netlists.
- The power-aware emulation model compilation flow has:
 - Similar UPF constructs are supported between simulation and emulation environments.
 - Debug continuity across PA-Simulation and PA-Emulation.







Compiling a PA Emulation Design Target

- Makefile changes and identifying compilation options that need to change for running low-power scenarios.
- □While compiling, we need to fix any errors that may come due to any power related ports for any IP instances.
- □We also need to ensure the availability of complete list of UPF libraries to be included.
- Next step is to use the available utility to convert present libraries to Emulation compatible libraries.
- □After that we can run lib to DB conversion script and convert libraries to the format needed.
- After all this, once we fix all the UPF compilation issues related to version or any specific tool option, we can run our basic single/multi core power down scenarios to verify that the intent of the test has been achieved.







Power Aware Compilation Flow

- This methodology ensures that all synthesizable design components are reused between PA Simulation and PA Emulation.
- This means now we can use both platforms to complement each other in the Validation lifecycle with a high degree of confidence.
- We have efficiently offloaded long running power aware scenarios to the PA Emulation environment to bring down the testing time to a fraction of what it was in the PA Simulation environment.







Some Common Issues

✓ Clash of Rules and Design Attributes amongst various IPs:

Enabling/disabling of power well biases varies from one IP to another and sometimes clashes with the power bias enabled/disabled rule at the SoC level. To resolve this, we had set enable_bias to false for all IPs and the SoC top.

✓ *Corrupt cell libraries:*

Cell libraries for various IPs have vastly different release schedules and hence during integration, sometimes we can end up with stale and corrupt lib paths which need to be updated manually. Error- [UPF_ATTR_VALUE_MISMATCH] Attribute value different from parent /disk/path/to/ip/A/ipA_top.upf, 20 Attribute 'enable_bias' has been specified in an ancestor hierarchy as 'false'. Cannot specify attribute as 'true' in scope

Error- [CFCILFBI] Cannot find cell in liblist /disk/path/to/ip_A/design/files/RTL/ip_A_prj_<size>_ram_<attr>.v, 162 Cell 'ip_A_<process>_<size>_rtl_top' cannot be found in liblist for binding instance `top.dut.<ip_A_soc_hierarchy>.cell_name Liblist: WORKLIB ip_A DEFAULT





Some Enhancements Done







Results

CADENCE PLATFORM									
Test Category	No. of clock cycles	RTL Simulation Time	Emulation Run Time	Speedup	Simulation				
	Millions	(sec)	(sec)	9⁄0	ପ୍ ପ 25000				
Category 1	8.641	20529	1020	95.0314	<u>s</u> 20000				
Category 2	5.182	10715	645	93.9804	15000 10000				
Category 3	6.526	18654	840	95.4969	25000 20000 15000 10000 10000 1 2 3				
Category 4	7.951	23279	960	95.8761					
Category 5	7.375	21782	971	95.5422					
Category 6	7.250	17458	911	94.7818	S.				
Category 7	6.404	18580	765	95.8827	Simulation Time (Left Ax				
Category 8	5.530	16381	785	95.2079					
Test Category	No. of clock cycles	RTL Simulation Time	Emulation Run Time	Speedup	Simulation				
	Millions	(sec)	(sec)	9⁄0	25000				
Category 1	9.199	20492	307	98.5019	20000 9 15000				
Category 2	9.056	23235	288	98.7605	15000				
Category 3	7.374	18065	322	98.2175	5000				
Category 4	8.641	20529	331	98.3876					
Category 5	6.526	18654	268	98.5633	25000 20000 15000 15000 15000 1 2 3				
Category 6	7.951	23279	275	98.8187	S				
Category 7	7.375	21782	273	98.7467	Simulation Time (Left A				
Category 8	7.374	18432	275	98.5080					

Test Category	RTL Simulation Time	Emulation Run Time	Speedup	300000 -	Simulation \
0.	(sec)	(sec)	%	<u>8</u> 200000 -	
Category 1	116877	2417	97.9320	E 100000	
Category 2	119090	2733	97.7051	100000 -	
Category 3	70703	4027	94.3043	Si O	1 2
Category 4	267216	7782	97.0877		Te Simulation Time (Left A



•







Conclusion

- Multiple long-running scenarios can be smoothly ported onto an emulation platform and are much easier and faster than simulation.
- The experiments were carried out for several functional and low power scenarios along with simulation for the same scenario on same design drop for comparison.
- The run times were recorded and analyzed. The corresponding plots are shown in Figure 16 as an indicator of the results.
- By using this method, we significantly reduced the number of iterations needed, debug time, and the verification schedule. Current results are indicative and based on two emulator platforms from vendors like Cadence and Synopsys.
- We also narrowed down the areas of critical bugs since we specifically aim to find relevant bugs early through this environment and not the complete coverage.
- Further enhancing the process by adding automation, verification engineer can maneuver between the two environments very easily as per the requirement.
- The results achieved in some of the Exynos Mobile SoCs and Automotive SoCs were demonstrative of the fact that we saved at least 50X time in closure of certain critical long pole features.





BENEFITS

Huge saving in SOC simulation run time

Scalable to various platforms across different designs

Major use case in low power functionalities

Has the potential to be applied to IO **Coherent scenarios**





LIMITATIONS









Acknowledgement

The authors would like to thank Samsung Semiconductors India Research for enabling the work mentioned in this paper. We would also like to thank DVCon Europe team for giving us the opportunity to participate in the conference and present our work.



